

**Pb-free perovskite solar cells composed of Sn/Ge(1:1) alloyed perovskite  
layer prepared by spin-coating**

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*Materials:* Tin(II) iodide ( $\text{SnI}_2$ , 99.99%), germanium (II) iodide ( $\text{GeI}_2$ , >99.8%), N, N-dimethylformamide (DMF), dimethyl sulfoxide (DMSO), chlorobenzene (CB), n-pyrrolidinone (NMP) were purchased from Sigma-Aldrich. Methylamine Hydroiodide (MAI, Low water content, >99.0%) was purchased from Tokyo Chemical Industry Co., Ltd. Poly(3,4-ethylenedioxythiophene)-poly(styrene sulfonate) (PEDOT: PSS) was obtained from CLEVIOS PVP AI 4083.

*Device Fabrication:* The glass was cleaned with water, acetone, and isopropanol sequentially for 15 min. Then, the FTO was dried, followed by being treated with plasma for 5 min. PEDOT: PSS as hole transport layer was spin-coated on the FTO with 5000 rpm for the 50s. After that, the substrate was annealed at  $180^\circ\text{C}$  for 20 min. Then the substrate was transferred and kept in the  $\text{N}_2$ -filled glovebox. For the  $\text{MASn}_x\text{Ge}_{1-x}\text{I}_3$  perovskite solution, 1M  $\text{MASnI}_3$  (Sn 1soln) was prepared by mixing 1M MAI and 1M  $\text{SnI}_2$  in DMF. In the same way, 1M  $\text{MAGeI}_3$  solution (Ge 1soln) was obtained by dissolving 1M MAI and 1M  $\text{GeI}_2$  in DMF: NMP (v: v=4:1). They were stirred for 3 hours at room temperature inside the glove box, separately. 1M  $\text{MASn}_{0.5}\text{Ge}_{0.5}\text{I}_3$  ( $\text{Sn}_{0.5}\text{Ge}_{0.5}$  Non) was prepared from the Ge 1soln and Sn 1soln (1:1 mol). The perovskite layer of Device 1 was prepared as follows: 100  $\mu\text{L}$  of DMSO was added to the 1 mL Sn/Ge 1soln and the mixed solution ( $\text{Sn}_{0.5}\text{Ge}_{0.5}$  DMSO solution) was spin-coated, followed by an anti-solvent process, where 500  $\mu\text{L}$  of chlorobenzene (CB) was dropped on the film at 15s after the program started. Then, the film was annealed at  $70^\circ\text{C}$  for 20 min. The perovskite layer of the Device 2 was prepared as follows: 50  $\mu\text{L}$  of the mixture of (TEA: DMF=1:50 (v: v)) was added into  $\text{Sn}_{0.5}\text{Ge}_{0.5}$  Non. The mixed solution ( $\text{Sn}_{0.5}\text{Ge}_{0.5}$  TEA solution) was spin-coated on the PEDOP-PSS layer. The film was dried at room temperature. On each perovskite layer, fullerene ( $\text{C}_{60}$ : 20nm), 2,9-dimethyl-4,7-diphenyl-1,10-phenanthroline (BCP: 7 nm), and Ag (100 nm) were deposited to complete each device.

*Characterization:* The solar cell performances were measured by using a Keithley 4200 source meter and a solar simulator under  $100\text{mW cm}^{-2}$  AM 1.5G (Bunkouki CEP-2000SRR). The espoused area was fixed to  $0.1\text{ cm}^2$  using a non-reflective black metal mask. The EQE spectra were recorded using a monochromatic Xenon lamp (Bunkouki CEP-2000SRR). The EQE measurement was carried out under monochromatic light from 1200 to 300 nm (300W Xenon lamp with a monochromator, Newport 74010). The crystal structure was measured by

the XRD (Rigaku Smartlab XRD) with monochromatic Cu  $K_{\beta}$  irradiation (45 kV 200 mA). The bandgap of the film was estimated via the UV-Vis (JASCO V-670). XPS spectra were collected by Shimadzu Kratos Axis-Nova spectrometer. Mg  $K_{\alpha}$  excitation source was used at pass energy of 80 eV and the energy resolution was 1000 meV. PYS was measured using the Bunkoukeiki KV 205-HK ionization energy system with the applied voltaic of -10 V.

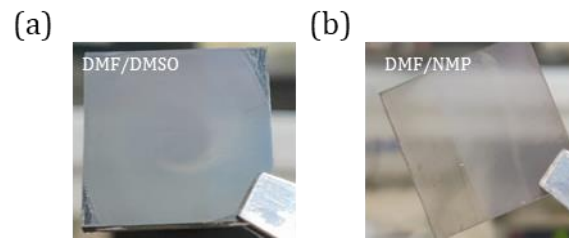


Fig. S1  $\text{MASn}_{0.5}\text{Ge}_{0.5}\text{I}_3$  perovskite film prepared with the solution of (a) DMF/DMSO (4:1) and (b) DMF/NMP (4:1).

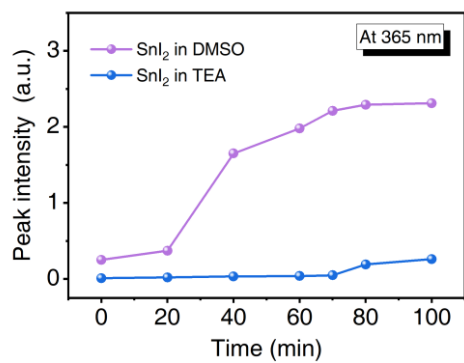


Fig. S2 Change of SnI<sub>2</sub> peak intensity in DMSO solution or TEA solution (DMSO solution: DMF:NMP:DMSO=4:1:0.5, volume; TEA solution: DMF:NMP:TEA=4:1:0.25, volume). The results were obtained from Fig. 1a-b.

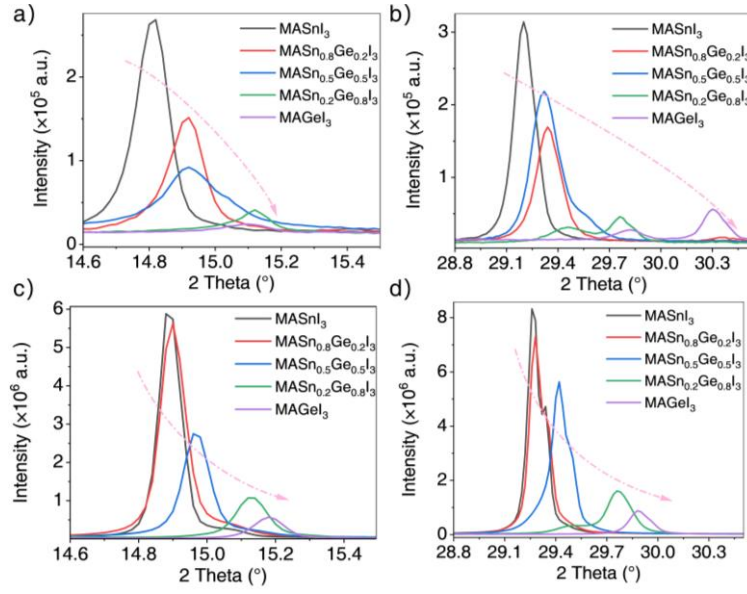


Fig. S3 (a-b) and (c-d) shows the partial enlarged view of Fig. 2a and Fig. 2b, respectively. It can be seen that with the increase of  $\text{Ge}^{2+}$ , the XRD peak position of the film gradually increases.

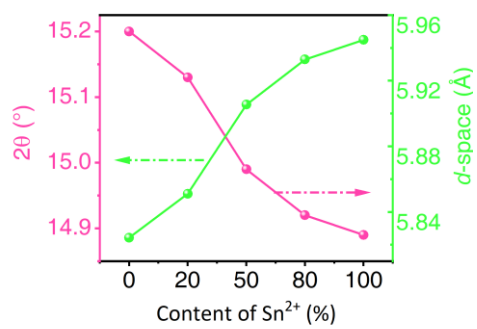


Fig. S4 (001) crystal plane peak position and  $d$ -space of  $\text{MASn}_x\text{Ge}_{1-x}\text{I}_3$  when  $x$  was changed.

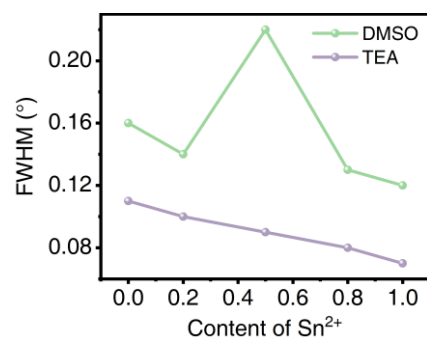


Fig. S5 Statistics of MASn<sub>x</sub>Ge<sub>1-x</sub>I<sub>3</sub> FWHM in Fig. S3a and Fig. S3c.



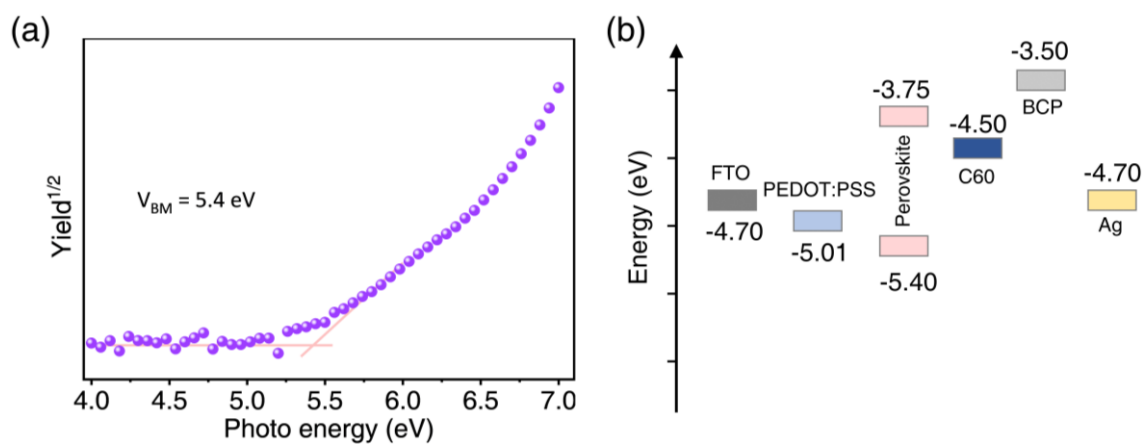


Fig. S6 (a) PYS spectra of MASn<sub>0.5</sub>Ge<sub>0.5</sub>I<sub>3</sub> perovskite films and (b) Energy level of each layer used in this work.

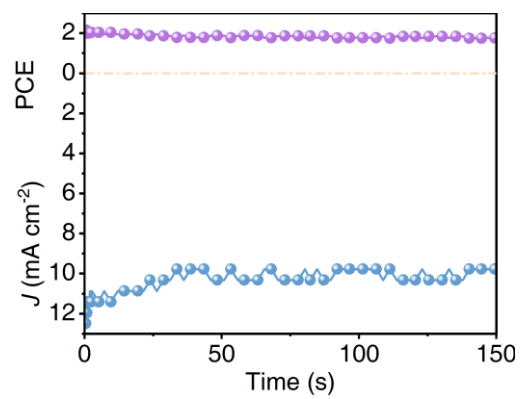


Fig. S7 Steady-state current density and PCE versus time for the best-performing devices employing  $\text{MASn}_{0.5}\text{Ge}_{0.5}\text{I}_3$  solar cell (Device 2) prepared from TEA solution. These were measured at the maximum power point.

**Table S1.** Photovoltaic parameters of best-devices prepared from various solution. They were measured in reverse and forward scans under AM 1.5G with one sun illumination of 100 mW/cm<sup>2</sup>.

Devices	Sweep	$J_{SC}$ (mA/cm <sup>2</sup> )	$V_{OC}$ (V)	FF	PCE (%)
Device 1	RS	10.15	0.280	0.480	1.36
	FS	9.25	0.260	0.47	1.13
Device 2	RS	11.04	0.380	0.530	2.18
	FS	10.09	0.360	0.500	1.81
Device 3	RS/FS				
Device 4	RS/FS				

Device 1 Prepared from DMF/NMP/DMSO (4:1:0.5) with antisovent

Device 2 Prepared from DMF/NMP/TEA (4:1:0.25) without anti-solvent

Device 3 Prepared from DMF/DMSO (4:1) with antisolvent

Device 4 Prepared from DMF/DMSO (4:1) with antisolvent